

Component Title:

Executive Member:

INTEGRATED CIRCUITS, SILICON MONOLITHIC, PULSE WIDTH MODULATOR $% \left(1,0\right) =0$

CNES

Date: 12/01/2023

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344C

Components (incl	uding series and fam	ilies) submit	ted for E	xtension	of Qua	alification .	Approval	:					
ESCC COMPONENT NO.				RANGE OF COMPONENTS			BASED ON)	TEST VEHICLE / S		COMPONE	
9108 020	01; 02						Type S	ST184	3	9108 020 01F		All variant	
9108 021	01; 02						Type S			9108 021 01R		All variant	
Component	Manufacturer	2	Location	on of Ma	anufacti	uring Plant	(s)	3	Г				4
ST Microelectronic	cs	Rer	Rennes 35041 - France							Date of original qualification approval:			
									Date:	14/11/	2016		
									Certific	cate Ref No.	344		
		5						6					7
ESCC Specification				o LVT te	esting a	nd Detail S	pecificat	ion		Qualification Extension Report			
Generic: 9000	ualification testing: 1 Issue: 1								reference and date: 33311002Z0 DC 2126A ST1843FKG Endurance Sg				
Generio.	10000.	. 110	Δ	100		15)	otolio iii t	JOX		005Z6 DC 2215			og
Detail(s): 9108/		Dev	Deviation from current Specifications:										
9108/021 5			No ⊠ Yes □ (Supply details)										
		""		100	_	(ouppi)	iotalioj						
									•				8
The second secon	rement or equivalent			N. V C C. V.	alidity p				plication		0000 0000 0000	VIII.75	
Project Name Testing Level			LAT Dat			Date code	e code Quantity Delivered						
PID changes since	start of qualification			9	Curre	ent PID V	erified by	r:		CNES (L. Baczkow	rski)	10
None 🗵									Nar	me of Excutive	Representa	tive	
Minor* □					Ref N	No: 8	303834 ((PWM) & 80970	046 (generic)			
Major* *Provide details in box:			Issue: 6			& 36		Date: 12/01/2022					
	1				Rev	Date: 2	7/11/201	8 & 03	3/10/2022	2			
					ONEO	/ ID 0					20/12	(0004	11
Current Manufactu	iring facilities surveye	ed by:	-			(JB Sauve		201 1900	on		08/10		
				(Name	e of Exe	ecutive Re	presentat	tive)			(Da	ite)	
Satisfactory:	Yes 🗵	N	0 🗆	Exp	olain								
Report Reference:	CR-Visite Oc	tohre 2021											
report reference.	OIT-VISITE OF	2021											

APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL Page 2 INTEGRATED CIRCUITS, SILICON MONOLITHIC, PULSE WIDTH Component title: Appl. No. MODULATOR **CNES** 12/01/2023 Executive Member: Date: 344C 12 Failure Analysis, DPA, NCCS available: Yes No \boxtimes (Supply data) Ref. No's and purposes: 13 The undersigned hereby certifies on behalf of the ESCC Executive - that the above information is correct; that the appropriate documentation has been evaluated; - that full compliance to all ESCC requirements is evidence (except as stated in box 15;) - that the reports and data are available at the ESCC Executive and therefore applies on behalf of CNES as the responsible Executive Member for ESCC qualification status to be extended to the component(s) listed herein. Date: 13/01/2023 G. QUADRI, CNES (Signature of the Executive Coordinator) 14 Continuation of Boxes above:

Component title:

INTEGRATED CIRCUITS, SILICON MONOLITHIC, PULSE WIDTH MODULATOR $% \left(1,0\right) =0$

CNES Executive Member:

Date: 12/01/2023

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Non comp	bilance to ESCC requirements:		
No.:	Specification	Paragraph	Non compliance
Additional	tanto considerad to cobine full compliance for	ECC qualification or rationals for accontability of	
noncompl	tasks required to achieve full compliance for l iance:	ESCC qualification or rationale for acceptability of	16
			-
Executive	Manager Disposition		47
			17
Applicatio	n Approval: Yes ☒ No □		
Action / R	emarks:		
Date:			3.81
Date.			B. Schade: Head of the Product Assurance and Safety Department



Component Title: INTEGRATED CIRCUITS, SILICON MONOLITHIC, PULSE WIDTH

MODULATOR

Executive Member: **CNES** 12/01/2023 Date:

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ANNEX 1: LIST OF TESTS DONE TO SUPPORT EXTENSION OF QUALIFICATION

Tests conducted in compliance with:

ESCC 9000 generic specification; Chart F4 (for ESCC/QPL parts);

Or PID-TFD (for ESCC/QML parts)

Tests vehicle identification/description:

ESCC 9108 020 01 ST1843FKG (33311002Z0) DC 2126 Chart F4 Endurance Subgroup ESCC 9108 021 01 ST1845RKG (lot id. 33306005Z6 DC 2215A Full Chart F4

Detail Specification reference:

9108/020; 9108/021

Chart F4	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if not performed. Comments on Rejection
	Mechanical Shock		MIL-STD-883, Test Method 2002	2215A	15	0	
	Vibration		MIL-STD-883, Test Method 2007	2215A	15	0	
	Constant Acceleration		MIL-STD-883, Test Method 2001	2215A	15	0	
	Seal (Fine and Gross Leak)		MIL-STD-883, Test Method 1014	2215A	15	0	
Environmental/Mechanical Subgroup	Intermediate and End-Point Electrical Measurements	\boxtimes	Intermediate and End-Point Electrical Measurements in the Detail Specification	2215A	15	0	
	External Visual Inspection		ESCC Basic Specification No. 20500	2215A	15	0	
	Thermal Shock		MIL-STD-883. Test Method 1011	2215A	15	0	
	Temperature cycling		MIL-STD-883, Test Method 1010	2215A	15	0	
	Moisture Resistance	\boxtimes	MIL-STD-883, Test Method 1004	2215A	15	0	
	Seal (Fine and Gross Leak)		MIL-STD-883, Test Method 1014	2215A	15	0	
	Intermediate and End-Point Electrical Measurements		Intermediate and End-Point Electrical Measurements in the Detail Specification	2215A	15	0	
	External Visual Inspection		ESCC Basic Specification No. 20500	2215A	15	0	



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Chart F4	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if not performed. Comments on Rejection
Endurance Subgroup	Operating Life	×	MIL-STD-883, Test Method 1005	2215A + 2126A	15 + 15	0	
	Intermediate and End-Point Electrical Measurements	×	Intermediate and End-Point Electrical Measurements in the Detail Specification	2215A + 2126A	15 + 15	0	
	Seal (Fine and Gross Leak)	×	MIL-STD-883, Test Method 1014	2215A + 2126A	15 + 15	0	
	External Visual Inspection		ESCC Basic Specification No. 20500	2215A + 2126A	15 + 15	0	,
Assembly Capability Subgroup	Permanence of Marking		ESCC Basic Specification No. 24800				Not applicable for laser marking
	Terminal Strength	\boxtimes	MIL-STD-883, Test Method 2004	2215A	5	0	,
	Internal Visual Inspection		ESCC Basic Specification No. 20400	2215A	5	0	
	Bond Strength	\boxtimes	MIL-STD-883 Test Method 2011	2215A	2	0	
	Die Shear or Substrate Attach Strength	Ø	MIL-STD-883 Test Method 2019 or 2027	2215A	2	0	
Additional Tests	RGA		MIL-STD-883 Test Method 1018.7				Only applicable to single phase qualification of Wire-bonded Integrated Circuits
Addit							



Box 22

Additional Comments.

APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL

INTEGRATED CIRCUITS, SILICON MONOLITHIC, PULSE WIDTH MODULATOR $% \left(1\right) =\left(1\right) \left(1$ Component title:

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NOTES ON THE COMPLETION OF THE APPLICATION FORM FOR ESCC QUALIFICATION EXTENSION APPROVAL

	HOTES OF THE COMPLETION OF THE ATTENDATION TO COMPLETE GOALS TO ATTENDED ATT NOVAL
ENTRIES Form heading	shall indicate: - the title of the component as given in its detail specification or the name of the series, family; - the Executive Member; - the entering date; - the certificate number and its sequential suffix.
Box 1	shall provide details given in the table; in particular there shall be listed: - the variants or range of variants; - the range of components (the ESCC code is recommended to indicate the values or values range, the tolerance, the voltage, etc); the designation given in the detail specification as 'base on'; - under Test Vehicle enter either an ESCC code or the specific characteristic capable of identifying the component tested (e.g., voltage of coil for a relay); - under component similar enter a cross if relevant.
Box 2; 3 and 4	As per QPL entry; otherwise, an explanation of the changes must be supplied.
Box 5	Will show the ESCC Generic and Detail specifications, including issue number and revision letter, current at the time the tests reported were performed. If the specifications are different from those current on the date of the application, see Box 6.
Box 6	Will show the deviations from the Generic and Detail Specifications listed in Box 5, in particular deviations from testing. In case of deviations this must be listed in Box 15. In case the referenced specification in Box 5 have currently a different issue and/or revision indicate also whether the test data deviates or not from such current documents.
Box 7	Must reference the report(s) supplied in support of the application.
Box 8	Should provide the details of procurement to the full ESCC System, documentation of all of which should already have been delivered to the ESCC Executive under the terms of the relevant Generic Specification. An appropriate table has been drawn in this box.
Box 9	If the PID evolved after the Original Qualification or after the last Extension of Qualification, adequate details of such evolution shall be provided together with the reasons for the changes. Major changes shall be clearly marked.
Box 10	Identify the current PID issue status, date and actual date of verification. The date of verification of the current PID should be arranged as close as possible to the required date of extension.
Box 11	This box can be completed only after a physical visit to the plant to confirm that no unexplained changes occurred and that the practices, procedures, material, etc. used in manufacturing the components are as described in the PID. This survey shall be carried out in accordance with the requirements of ESCC Basic Specification No. 20200 and its findings shall be recorded.
Box 12	Provide details of, or reference to, any Destructive Physical Analysis (DPA) and Failure Analysis reports as well as any Nonconformance(s) (NCCS) occurred during the qualification validity period, stating if established corrective action have produced satisfactory results.
Box 13	Enter only the name of the Executive Member (i.e., CNES, DLR, ESTEC, etc.) and the signature of the responsible Executive Coordinator.
Box 14	To be used when there is a need to expand any of the boxes from 1 through 12. Identify box affected and reference the Box 14 in the relevant Box. Box 14 can be broken into 14a, 14b, etc. if several boxes have to be expanded.
Box 15	Fill in Table as requested.
Box 16	Any additional action deemed necessary by the Executive Member to bring the submitted data to a standard likely to be accepted by the ESCC Executive should be listed herein or the reason(s) to accept the noncompliance.
Box 17	All Executive Manager recommendations on the application itself, special conditions or restrictions, modifications of the QPL or QML entry, letters to the manufacturer, etc. shall be entered clearly in Box 19, signed by the representative for ESA, and dated.
Box 18	Fill in Table as requested.
Box 19	Confidential Details of PID changes including those of a confidential nature, shall be provided.
Box 20	State noncompliance with reference to specification(s) and paragraph(s). To simplify reference in Box 16 each nonconformance shall be sequentially numbered. If relevant state 'None'.
Box 21	Any additional action deemed necessary by the Executive Member to bring the submitted data to a standard likely to be accepted by the ESCC Executive should be listed herein or the reason(s) to accept the noncompliance.